

RoHS

FQA7N80C_F109-VB Datasheet N-Channel 900V (D-S) Super Junction Power MOSFET

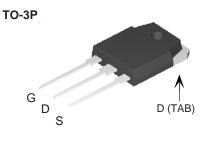
PRODUCT SUMMARY						
V _{DS} (V) at T _J max.	900					
R _{DS(on)} at 25 °C (Ω)	$V_{GS} = 10 V$	0.75				
Q _g max. (nC)	20					
Q _{gs} (nC)	2.4					
Q _{gd} (nC)	11					
Configuration	Single					

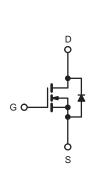
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)								
PARAMETER			SYMBOL	LIMIT	UNIT			
Drain-Source Voltage			V _{DS}	900	N			
Gate-Source Voltage			V _{GS}	± 30	V			
Continuous Drain Current (T _J = 150 °C)	V at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$		9				
	V _{GS} at 10 V	T _C = 100 °C	ID	7.3	A			
Pulsed Drain Current ^a			I _{DM}	28				
Linear Derating Factor				1.89	W/°C			
Single Pulse Avalanche Energy ^b			E _{AS}	86	mJ			
Maximum Power Dissipation			PD	109	W			
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C			
Drain-Source Voltage Slope	T _J = 125 °C		dV/dt	50	V/ns			
Reverse Diode dV/dt ^d			av/at	3.2	v/ns			
Soldering Recommendations (Peak Temperature) ^c	for 10 s			300	°C			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 3.5 A.

FQA7N80C_F109-VB



$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	THERMAL RESISTANCE RATI	NGS							
Maximum Junction-to-Case (Drain) R _{ILOC} - 0.7 "C/W SPECIFICATIONS (T_J = 25 °C, unless otherwise noted) PARAMETER SYMBOL TEST CONDITIONS Min. TYP. MAX. UNIT Static Drain-Source Breakdown Voltage V_{DS} $V_{CS} = 0$, $V_1 = 250 \mu A$ 900 - - V/V Gate-Source Dreakdown Voltage V_{DS} $V_{CS} = 0$, $V_1 = 250 \mu A$ 20 - 4 V/V Gate-Source Dreakdown Voltage V_{DS} $V_{DS} = 0$, $V_{SS} = 520 \mu A$ 2 - 4 V/V Gate-Source Lakage I_{QSS} $V_{CS} = 0$, $V_{CS} = 0$ - - ±100 nA Zero Gate Voltage Drain Current I_{DSS} $V_{OS} = 0$, $V_{CS} = 0$, $V_{CS} = 0$ - 10 - 0.75 - 10 Drain-Source On-State Resistance $P_{OS(en)}$ $V_{OS} = 0$, $V_{CS} = 0$, $V_{CS} = 0$ - 14 - - 26 - 14 - - 14 - - 266 - - <th>PARAMETER</th> <th>SYMBOL</th> <th colspan="2">TYP. MAX.</th> <th></th> <th colspan="3">UNIT</th>	PARAMETER	SYMBOL	TYP. MAX.			UNIT			
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}	- 72						
$\begin{array}{ c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$	Maximum Junction-to-Case (Drain)	R _{thJC}						°C/W	
$\begin{array}{ c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT Static $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$		•	•	•					
Static VDS VGS = 0 V, Ig = 250 µA 900 - - V Orain-Source Breakdown Voltage V_{DS} Reference to 25 °C, Ig = 1 mA - 0.65 - V/°C Gate-Source Threshold Voltage (N) $V_{QS}(m)$ $V_{DS} = V_{QS}$, Ig = 250 µA 2 - 4 V Gate-Source Leakage I_{QSS} $V_{DS} = 20 V$ - - ± 100 PA Zero Gate Voltage Drain Current I_{DSS} $V_{DS} = 900 V, V_{GS} = 0 V$ - - 1 μA Drain-Source On-State Resistance $R_{DS(m)}$ $V_{DS} = 00 V, V_{GS} = 0 V$ - - 10 μA Forward Transconductance g_{1s} $V_{DS} = 10 V$ $I_D = 6 A$ - 19 - S Dynamic Input Capacitance C_{cass} $V_{DS} = 0 V, V_{DS} = 0 V$ - 373 - - 46 - 19 - 82 - 14 - PF PE $10 \pm 0 \times 0, V_{DS} = 0 V$ $V_{DS} = 0 V, V_{DS} = 0 V$ $V_{DS} = 0 \times 0, $	SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$, u	Inless otherwi	se noted)						
$\begin{array}{ c c c c c c } \hline Drain-Source Breakdown Voltage V_{DS} & $V_{QS} = 0 V, $l_{D} = 250 μA & 900 - $ & $-$ & V \\ \hline V_{DS} Temperature Coefficient $\Delta V_{DS} T_J$ & Reference to 25 °C, $l_{D} = 1 mA $ & $-$ & 0.65 & $-$ & V^{*C} \\ \hline Gate-Source Threshold Voltage (N) $V_{QS}(m)$ & $V_{DS}, $l_{D} = 250 μA & 2 & $-$ & 4 & V \\ \hline Gate-Source Leakage l_{QS} & $V_{QS} = 2.0 V$ & $-$ & $-$ & $\pm 1.0 μA \\ \hline V_{QS} = $\pm 20 V$ & $-$ & $-$ & $\pm 1.1 μA \\ \hline V_{QS} = $\pm 30 V$ & $-$ & $-$ & $\pm 1.1 μA \\ \hline V_{QS} = $\pm 20 V$ & $V_{QS} = 0 V$, $V_{QS} = 0 V$ & $-$ & $-$ & 10 μA \\ \hline Drain-Source On-State Resistance $P_{DS}(m)$ & $V_{DS} = 60 V$, $V_{QS} = 0 V$, $T_{J} = 125 °C$ & $-$ & $-$ & 10 μA \\ \hline Drain-Source On-State Resistance $P_{DS}(m)$ & $V_{DS} = 30 V$, $l_{D} = 6 A$ & $-$ & 0.75 & $-$ Ω \\ \hline Drain-Source On-State Resistance $P_{DS}(m)$ & $V_{DS} = 30 V$, $l_{D} = 6 A$ & $-$ & 0.75 & $-$ Ω \\ \hline Drain-Source On-State Resistance $P_{CS}(m)$ & $V_{DS} = 100 V$, $l_{D} = 6 A$ & $-$ & 0.75 & $-$ Ω \\ \hline Drain-Source On-State Resistance C_{ras} & $V_{DS} = 100 V$, $l_{D} = 6 A$ & $-$ & 0.75 & $-$ Ω \\ \hline Reverse Transfer Capacitance C_{cas} & $V_{DS} = 100 V$, $l_{D} = 6 A$ & $-$ & 0.75 & $-$ Ω \\ \hline Reverse Transfer Capacitance, C_{ras} & $V_{DS} = 0 V$, $V_{CS} = 0 V$ \\ \hline PF \\ \hline Total Gate Charge Q_{gs} \\ Gate-Drain Charge Q_{gs} \\ Gate-Drain Charge Q_{gs} \\ Gate-Drain Charge Q_{gs} \\ Gate-Drain Charge Q_{gs} \\ Fall Time t_{10} \\ Fall Time t_{10} \\ Fall Time t_{1} \\ Gate Input Resistance R_{g} $f = 1 MHz$, open drain$ $-$ $ 3.5 $-$ Ω \\ \hline \ Drain-Source Body Diode Characteristics $V_{CS} = 0 V$ \\ \hline \ Dial P = 0 Riverse Recovery Time t_{1} \\ \hline \ Proverse Recovery Charge Q_{SD} \\ \hline \ Dial de Forward Voltage V_{SD} V_{SD} $V_{SD} = C_{1} $V_{SD} = C_{1} $V_{SD} = C_{1} V_{SD} $-$ C_{1} T_{1} $V_{CS} = C_{1} $V_{SD} = C_{1} $V_{SD} = C_{1} V_{SD} $V_{SD} = C_{1} V_{SD} $V_{SD} = C_{1} V_{SD} $V_{SD} = C_{1} $V_{$	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static						•	•	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	900	-	-	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.65	-	V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V _{GS(th)}				2	-	4	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		_	$V_{GS} = \pm 20 V$		V	-	-	± 100	nA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	I _{GSS}				-	-	± 1	μA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $						-	-	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	I _{DSS}					-	10	μA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source On-State Resistance	R _{DS(on)}				-	0.75	-	Ω
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance		V _{DS}	= 30 V, I _D	= 6 A	-	19	-	S
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic						•	•	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Input Capacitance	C _{iss}	V _{DS} = 100 V,		-	373	-	pF	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}			-	26	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance				-	14	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	1 1 7 00	C _{o(er)}	V_{DS} = 0 V to 520 V, V_{GS} = 0 V		-	46	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C _{o(tr)}			-	64	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg	$V_{GS} = 10 \text{ V}$ $I_D = 6 \text{ A}, V_{DS} = 520 \text{ V}$			-	26		nC
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge	Q _{gs}			A, V _{DS} = 520 V	-	2.1	-	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge	Q _{gd}				-	2.8	-	
Turn-Off Delay Time $t_{d(off)}$ $V_{DD} = 620$ V, $I_D = 6$ A, $V_{GS} = 10$ V, $R_g = 9.1 \Omega$ $ 71$ $ 71$ $ 71$ $ 71$ $ 71$ $ 71$ $ 71$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ $ 411$ $ 71$ <t< td=""><td>Turn-On Delay Time</td><td>t_{d(on)}</td><td colspan="2" rowspan="4"></td><td>-</td><td>26</td><td>-</td><td rowspan="4">ns</td></t<>	Turn-On Delay Time	t _{d(on)}			-	26	-	ns	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r			-	55.7	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-Off Delay Time	t _{d(off)}			-	71	-		
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode-7APulsed Diode Forward CurrentIsMIsMT_J = 25 °C, I_S = 6 A, V_{GS} = 0 V1.8Diode Forward VoltageV_{SDT_J = 25 °C, I_S = 6 A, V_{GS} = 0 V1.4VReverse Recovery TimetrrT_J = 25 °C, I_F = I_S = 6 A, dl/dt = 100 A/µs, V_R = 400 V-2.4-µC	Fall Time	t _f			-	41	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Input Resistance	R _g	f = 1 MHz, open drain		-	3.5	-	Ω	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Body Diode Characteristi	cs							
Pulsed Diode Forward CurrentIsmIntegral reverse p - n junction diode18Diode Forward Voltage V_{SD} $T_J = 25 \ ^{\circ}C$, $I_S = 6 \ A$, $V_{GS} = 0 \ V$ 1.4VReverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 6 \ A$, dl/dt = 100 A/µs, $V_R = 400 \ V$ -1.4V	Continuous Source-Drain Diode Current	IS	showing the integral reverse		-	-	7	A	
$ \begin{array}{c c} \mbox{Reverse Recovery Time} & t_{rr} & & \\ \mbox{Reverse Recovery Charge} & Q_{rr} & & T_J = 25 \ ^\circ C, \ I_F = I_S = 6 \ A, \\ \ dI/dt = 100 \ A/\mu s, \ V_R = 400 \ V & & \\ \end{array} \\ \begin{array}{c c} - & 192 & - & ns \\ \hline - & 2.4 & - & \mu C \\ \end{array} $	Pulsed Diode Forward Current	I _{SM}			-	-	18		
$ \begin{array}{c c} \mbox{Reverse Recovery Time} & t_{rr} & & \\ \mbox{Reverse Recovery Charge} & Q_{rr} & & T_J = 25 \ ^\circ C, \ I_F = I_S = 6 \ A, \\ \ dI/dt = 100 \ A/\mu s, \ V_R = 400 \ V & & \\ \end{array} \\ \begin{array}{c c} - & 192 & - & ns \\ \hline - & 2.4 & - & \mu C \\ \end{array} $	Diode Forward Voltage	V _{SD}	$T_J = 25 \text{ °C}, I_S = 6 \text{ A}, V_{GS} = 0 \text{ V}$		-	-	1.4	V	
Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 6 \ A$, $dI/dt = 100 \ A/\mu s$, $V_R = 400 \ V$ -2.4- μC					-	192	-	ns	
	Reverse Recovery Charge				-	2.4	-	μC	
	, ,				-	11	-	-	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

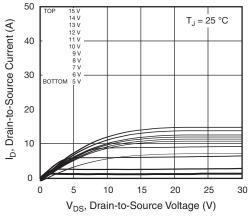


Fig. 1 - Typical Output Characteristics

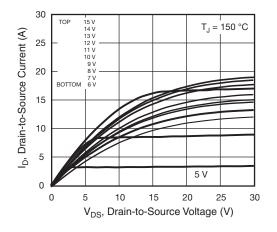


Fig. 2 - Typical Output Characteristics

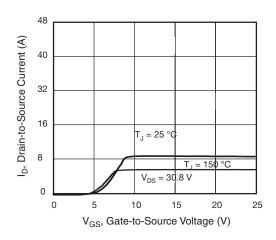


Fig. 3 - Typical Transfer Characteristics

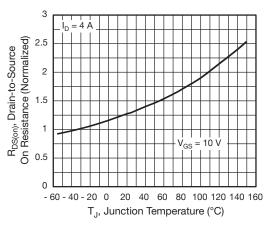


Fig. 4 - Normalized On-Resistance vs. Temperature

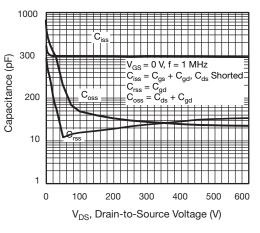


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

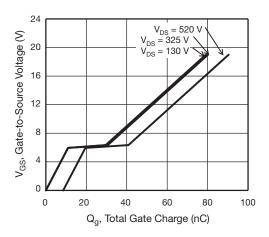


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

FQA7N80C_F109-VB



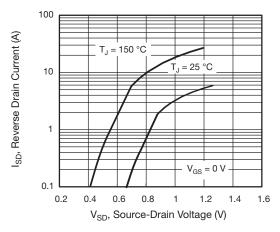


Fig. 7 - Typical Source-Drain Diode Forward Voltage

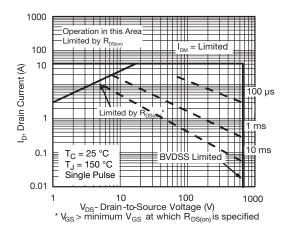


Fig. 8 - Maximum Safe Operating Area

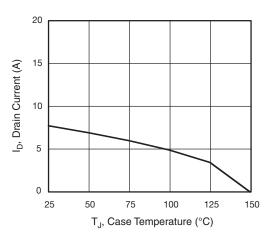


Fig. 9 - Maximum Drain Current vs. Case Temperature

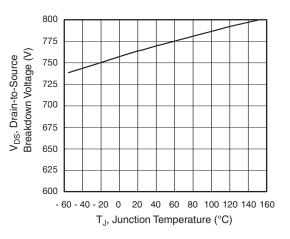


Fig. 10 - Temperature vs. Drain-to-Source Voltage

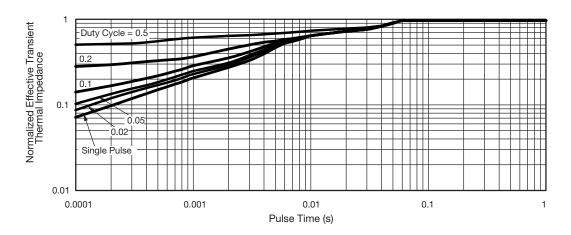


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



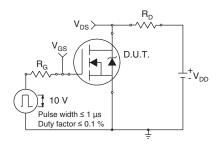


Fig. 12 - Switching Time Test Circuit



Fig. 13 - Switching Time Waveforms

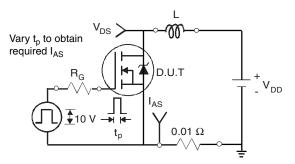


Fig. 14 - Unclamped Inductive Test Circuit

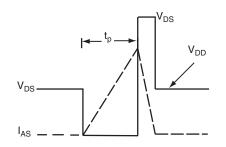


Fig. 15 - Unclamped Inductive Waveforms

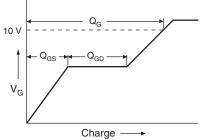


Fig. 16 - Basic Gate Charge Waveform

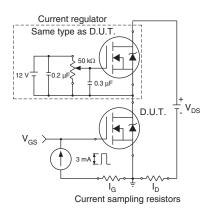
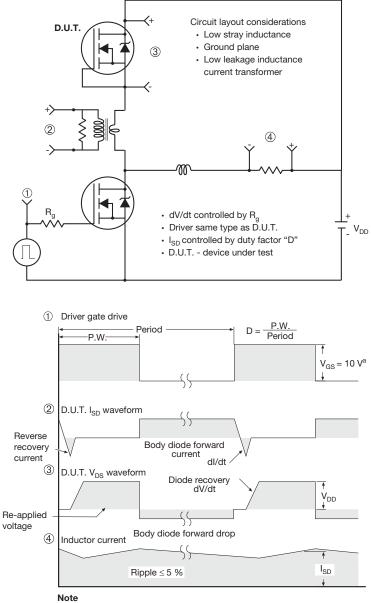


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5 V$ for logic level devices

Fig. 18 - For N-Channel



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